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## Agenda

- Design Phases
- General Design Approach
  - Top Level Flow
  - Block Level Flow
- Chip Planning
  - FloorPlanning
  - Pin Assignment
- Logic Synthesis
- Placement
- Routing

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- Placement Driven Synthesis
- Timing Analysis
- Power Analysis
- Noise analysis

#### **Design of Integrated Circuits**

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#### System Level

- Abstract algorithmic description of high-level behavior
  - e.g. C-Programming language

- abstract because it does not contain any implementation details for timing or data
- efficient to get a compact execution model as first design draft
- difficult to maintain throughout project because no link to implementation

#### RTL Level

Cycle accurate model "close" to the hardware implementation

- bit-vector data types and operations as abstraction from bitlevel implementation
- sequential constructs (e.g. if then else) to support modeling of complex control flow

```
module mark1;
reg [31:0] m[0:8192];
reg [12:0] pc;
reg [31:0] acc;
reg[15:0] ir;
always
    begin
        ir = m[pc];
        if(ir[15:13] == 3b'000)
            pc = m[ir[12:0]];
        else if (ir[15:13] == 3'b010)
            acc = -m[ir[12:0]];
        ...
end
endmodule
```

#### Gate Level

- Model on finite-state machine level
  - models function in Boolean logic using registers and gates
  - various delay models for gates and wires



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#### Transistor Level

- Model on CMOS transistor level
  - depending on application function modeled as resistive switches
    - used in functional equivalence checking
  - or full differential equations for circuit simulation
    - used in detailed timing analysis



#### Layout Level

Transistors and wires are laid out as polygons in different technology layers such as diffusion, polysilicon, metal, etc.



#### **Design Progression**

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- Design phases overlap to large degrees
- Parallel changes on multiple levels, multiple teams
- Tight scheduling constraints for product



#### **Project Time**

## Design Challenges

- Systems are becoming huge, design schedules are getting tighter
  - > 2 billion transistors for high end processors
  - > Half Million lines of C-code to describe system behavior
  - > 5-10 Million lines of RTL code
  - > 50 Million gates becoming common for ASICs
- Design teams are getting very large for big projects
  - several hundred people spread across the globe
  - differences in skills
  - concurrent work on multiple levels
  - management of design complexity and communication very difficult
- Design tools are becoming more complex but still evolving
  - typical designer has to run ~50 tools on each component
  - tools have bugs, interfaces do not line up etc.

#### Design Challenges

- Decision about design point very difficult
  - compromise between performance / costs / time-to-market
  - decision has to be made > 3 years before design finished
  - design points are increasingly difficult to predict without actually doing the design
  - scheduling of product cycles
- Functional verification

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- simulation still main vehicle for functional verification but inadequate because of size of design space
- results in bugs in released hardware that is very expensive to recover from (different in software ;-)

#### General Design Approach

- How do engineers build a bridge?
- Divide and conquer !!!!
  - partition design problem into many sub-problems which are manageable
  - define mathematical model for sub-problem and find an algorithmic solution
    - beware of model limitations and check them !!!!!!!
  - implement algorithm in individual design tools, define and implement general interfaces between the tools
  - implement checking tools for boundary conditions
  - concatenate design tools to general design flows which can be managed
  - see what doesn't work and start over

#### Generic Design Hierarchy



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#### Hierarchical Design Flow: Top Level Flow



Hierarchical Design Flow: Macros





#### Chip Planning



## Chip partitioning



Collection of cut edges Cut set: (1,3), (2,3), (5,6),

#### FloorPlanning

Example Given: Three blocks with the following potential widths and heights Block A: w = 1, h = 4 or w = 4, h = 1 or w = 2, h = 2Block B: w = 1, h = 2 or w = 2, h = 1Block C: w = 1, h = 3 or w = 3, h = 1

Task: Floorplan with minimum total area enclosed



#### FloorPlanning

#### Example

Given: Three blocks with the following potential widths and heights Block A: w = 1, h = 4 or w = 4, h = 1 or w = 2, h = 2Block B: w = 1, h = 2 or w = 2, h = 1Block C: w = 1, h = 3 or w = 3, h = 1

Task: Floorplan with minimum total area enclosed



#### FloorPlanning

Example Given: Three blocks with the following potential widths and heights Block A: w = 1, h = 4 or w = 4, h = 1 or w = 2, h = 2Block B: w = 1, h = 2 or w = 2, h = 1Block C: w = 1, h = 3 or w = 3, h = 1

Task: Floorplan with minimum total area enclosed



Solution: Aspect ratios Block A with w = 2, h = 2; Block B with w = 2, h = 1; Block C with w = 1, h = 3

This floorplan has a global bounding box with minimum possible area (9 square units).

#### Floorplanning – Optimization Goal

- Area and shape of the global bounding box
  - Area of the global bounding box represents the area of the top-level floorplan
  - Minimizing the area involves finding (*x*,*y*) locations, as well as shapes, of the individual blocks.
- Total wirelength
  - Long connections between blocks may increase signal propagation delays in the design.
- Combination of area area(F) and total wirelength L(F) of floorplan F
  - Minimize 

     *area*(*F*) + (1 − 
     *L*(*F*)
     where the parameter 0 ≤ 
     ≤ 1 gives the relative importance between *area*(*F*) and *L*(*F*)
- Algorithms

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- Floorplan Sizing find minimum floorplan area for a slicing floorplan in polynomial time. For Non slicing floorplan the problem is NP hard
- Cluster Growth Iteratively add blocks to the cluster until all blocks are assigned
- Simulated Annealing Iterative in nature

Logic Synthesis

- Input: RTL; Output: Gate level optimized netlist
- Objective:
  - Minimize area
    - in terms of literal count, cell count, register count, etc.
  - Minimize power
    - in terms of switching activity in individual gates, deactivated circuit blocks, etc.
  - Maximize performance
    - in terms of maximal clock frequency of synchronous systems, throughput for asynchronous systems
  - Any combination of the above
    - combined with different weights
    - formulated as a constraint problem
      - "minimize area for a clock speed > 3 GHz"
  - More global objectives
    - feedback from layout: actual physical sizes, delays, placement and routing

#### Logic Synthesis

Logic Synthesis Sub-steps...



#### Placement

- Input
  - Netlist of connected circuit elements and nets
- Output
  - Exact locations of circuit elements without overlaps
- Goal is to guarantee routability, but extremely difficult to model this
- Usually use wirelength minimization
  - Length(net i)
- How to estimate length of a net
  - Half perimeter wire length model (HPWL)
  - Minimum Spanning Tree (MST)
  - Steiner Tree (ST)

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#### Placement



2D Placement

Placement and Routing with Standard Cells

## Placement - Steps

#### Global Placement







#### Routing

#### Input

- Placed netlist and technology information
- Output
  - Physically connected cells
- Goal is to
  - determine the necessary wiring, e.g., net topologies and specific routing segments, to connect these cells
  - while respecting constraints, e.g., design rules and routing resource capacities, and
  - optimizing routing objectives, e.g., minimizing total wirelength and maximizing timing slack

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#### Routing Overview



#### Routing Overview

Netlist:  $N_1 = \{C_4, D_6, B_3\}$  $N_2 = \{D_4, B_4, C_1, A_4\}$ 3 4 1  $N_4 = \{B_1, A_1, C_3\}$ 2 1 A 4  $N_1$ 1 B 3 6 4 5 **Technology Information** 4 D (Design Rules)

#### Routing Overview

#### Netlist:

 $N_{1} = \{C_{4}, D_{6}, B_{3}\}$   $N_{2} = \{D_{4}, B_{4}, C_{1}, A_{4}\}$   $N_{3} = \{C_{2}, D_{5}\}$   $N_{4} = \{B_{1}, A_{1}, C_{3}\}$ 

Technology Information (Design Rules)



## **Routing Steps**



#### What is Physical Synthesis?

# Combines multiple separate steps into one to perform timing (design) closure



#### **Physical Synthesis Nuts and Bolts**



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#### **Physical Synthesis Flow**



#### Static Timing Analysis

- Purpose
  - Ensure design will operate properly at a target frequency
- Inputs
  - Netlist
  - Library rules
  - User-specified assertions/constraints
- Outputs
  - List of (failing) tests
  - List of (failing) paths
  - Abstract

Courtsey:K. Kalafalla

#### What is timing analysis?

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> Problem: My boss usually leaves home at 7:30 a.m. At what time should I leave home to be absolutely sure I reach the office before him?



#### Slight twist on the problem

Problem: My boss usually leaves home at 7:30 a.m. If I also leave home at 7:30 a.m., does that give me some <u>slack</u>?



Answer: I arrive <u>no later than</u> 7:30 + 10 + 5 = 7:45 = <u>my late arrival time</u> My boss arrives <u>no sooner than</u> 7:30 + 30 – 10 = 7:50 = <u>his early arrival time</u> My <u>required arrival time</u> = my boss's early arrival time = 7:50 a.m. I have <u>slack</u> = required arrival time – arrival time = at least 5 minutes!



My boss's commute:

30 mins.

-10 mins. for "early mode"

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#### So it is with circuits: setup tests



#### Hold tests



#### Timing analysis of circuits

> With every signal, we associate four arrival times

- Early (rise and fall)
- Late (rise and fall)
- Late arrival time is 100 ps means, "if at all a signal switches in any given cycle, it will be stable after 100 ps"
- Early arrival time is 50 ps means, "if at all a signal switches in any given cycle, it will not change from its previous cycle stable value sooner than 50 ps"
- Setup test: compare late data arrival time to early clock
- Hold test: compare early data arrival time to late clock
- Requires just one simple pass of the circuit (or "timing graph");

#### Power

- Dynamic
  - Power due to Signal transitions.
  - Short Circuit component.
- Static
  - Leakage power (due to leakage currents).
- Clock Power

#### **Power Components**

**Dynamic power** 



#### Leakage Power

- Three dominant leakage mechanisms:
  - Subthreshold Leakage -Strong dependence on VDD, Process and Temperature
  - Gate Oxide Leakage -Strong dependence on VDD and Tox
  - Drain Junction Leakage

     Reverse Bias current
     between Source/Drain and
     the substrate, due to high
     doping concentrations.

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Factors affecting Dynamic Power

# Pavg = 0.5 \* C<sub>load</sub> \* VDD<sup>2</sup> \* f \* SF

- **Capacitance :** Function of fan-out, wire length, transistor sizes
- Supply Voltage : The quadratic term has been dropping with successive generations
- Activity factor : How often, on average, do wires switch
- Clock frequency : Increasing, and now decreasing with the new multi-core and many-core systems.

#### Verification



Courtsey:K. W. Roesner

# Late Engineering Changes (ECOs)

#### New(Modified) RTL

%EPINS TurboVHDL: End Pins :475	Definition:474
%entity:476	
Entity 13cpr zmac Is:192	
Port (:192	
g <mark>nd</mark>	: Inout power_logic;
:195,	
vdd	<pre>: Inout power_logic;</pre>
:194,	
act	: In std_ulogic;
:204,	
align_0	: In std_ulogic;
:198,	
func_scan_in	: In std_ulogic;
:207,	
func_scan_in_opt	: In std_ulogic_vecto

#### **Original Synthesized/Routed Netlist**



#### **Modified Circuit**



#### ECO Flow



#### Release to Manufacturing

- Final edits to the layout are made
- Metal fill and metal stress relief rules are checked
- Manufacturing information such as scribe lanes, seal rings, mask shop data, part numbers, logos and pin 1 identification information for assembly are also added
- DRC and LVS are run to verify the correctness of the modified database; Electrical rule checking;
- 'Tapeout' documentation is prepared prior to release of the GDSII to the foundry
- Pad location information is prepared, typically in a spreadsheet
- Custom-manual edits of the mask layers
- Manufacturing steps
  - generation of masks; silicon processing; wafer testing; assembly and packaging; manufacturing test